Docket No.: P2001,0097

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

**Applicant** 

DETLEV RICHTER

Filed

CONCURRENTLY HEREWITH

Title

SEMICONDUCTOR MODULE WITH A CONFIGURATION FOR THE SELF-TEST OF A PLURALITY OF INTERFACE CIRCUITS AND TEST

**METHOD** 

## INFORMATION DISCLOSURE STATEMENT

Hon. Commissioner of Patents and Trademarks, Washington, D.C. 20231

Sir:

In accordance with 37 C.F.R. 1.98 copies of the following patents and/or publications are submitted herewith:

German Published Non-Prosecuted Patent Application DE 198 32 307 A1 (Schaffroth et al.), dated February 3, 2000, integrated circuit with self-testing device;

German Patent Application DE 199 01 460 C1 (Daehn), dated August 31, 2000, integrated circuit and procedure for functional testing of bond pad cells;

If no translation of pertinent portions of any foreign language patents or publications mentioned above is included with the aforementioned copies of those applications, patents and/or publications, it is because no existing translation is readily available to the applicant.

Respectfully submitted,

For Applicant

WERNER H. STEMER

REG. NO. 34,956

Date: February 13, 2002

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/kf







<b>FORM PTO-1449</b>	(SUBSTITL	JTE)
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U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

INFORMATION DISCLOSURE STATEMENT BY APPLICANT (37 CFR 1.98(b))

Attorney	Docket	No.:	P2001	,0097
Appl. No.				

Applicant DETLEV RICHTER

Filing Date February 13, 2002 Group Art Unit



EXAMINER INITIALS		PATENT NO.	DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE
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## FOREIGN PATENT DOCUMENT

	DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB CLASS	TRAI YES	
J	198 32 307 A1	2/3/00	Germany				
K	199 01 460 C1	8/31/00	Germany				
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OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

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**EXAMINER** 

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.